

 PRODUCT

SENSORS

POINT SENSORS - CONFOCAL WHITE LIGHT

The P-CHR sensors are high end confocal sensors, based on the principal of chromatic aberration. They offer maximum accuracy and high speed. Highlights in this sensor series are measurement heads with a high numeric aperture.

MODEL	RESOLUTION	MEASUREMENT RANGE	WORKING DISTANCE	SPOT SIZE
P-CHR-100	0.003 µm	0.12 µinch	100 µm	3.9 mils
P-CHR-300	0.01 µm	0.39 µinch	300 µm	11.8 mils
P-CHR-350	0.012 µm	0.47 µinch	350 µm	13.8 mils
P-CHR-400	0.014 µm	0.55 µinch	400 µm	15.7 mils
P-CHR-600	0.02 µm	0.79 µinch	600 µm	23.6 mils
P-CHR-1000	0.035 µm	1.38 µinch	1000 µm	39.4 mils
P-CHR-2000	0.07 µm	2.76 µinch	2000 µm	78.7 mils
P-CHR-2000	0.07 µm	2.76 µinch	2000 µm	78.7 mils
P-CHR-3000	0.10 µm	3.94 µinch	3000 µm	118 mils
P-CHR-6000	0.20 µm	7.87 µinch	6000 µm	236 mils
P-CHR-8000	0.28 µm	11.02 µinch	8000 µm	315 mils
P-CHR-10000	0.30 µm	11.80 µinch	10 mm	0.39 inch
P-CHR-12000	0.40 µm	15.75 µinch	12 mm	0.47 inch
P-CHR-15000	0.50 µm	19.69 µinch	15 mm	0.59 inch
P-CHR-25000	0.80 µm	31.50 µinch	25 mm	0.98 inch

POINT SENSORS - LASER CONFOCAL AND LASER TRIANGULATION

The confocal laser sensor uses a blue laser source and is ideally for measuring solar cells. The DSR-500 is ideal for measuring thick-film on a variety of substrates.

MODEL	RESOLUTION	MEASUREMENT RANGE	WORKING DISTANCE	SPOT SIZE
LT-9510	0.01 µm	0.39 µinch	200 µm	7.9 mils
DRS-500	0.125 µm	4.92 µinch	500 µm	19.7 mils

POINT SENSORS - INTERFEROMETER FOR THICKNESS MEASUREMENT

A white light interferometer measures the thickness of transparent materials and films. Various infrared interferometers are available for measuring wafer thickness as well as glue and epoxy films.

MODEL	RESOLUTION	MEASUREMENT RANGE	WORKING DISTANCE	SPOT SIZE
INT-180 (WL)	0.01 µm	0.39 µinch	3 µm - 180 µm	0.12 mils - 7.09 mils
IT-500 (IR)	0.14 µm	5.51 µinch	37 µm - 4700 µm	1.46 mils - 185.0 mils
IT-500 RW (IR)	0.17 µm	6.69 µinch	45 µm - 5600 µm	1.77 mils - 220.5 mils
IT-1000 (IR)	0.25 µm	9.84 µinch	64 µm - 8200 µm	2.52 mils - 322.8 mils
IT-1000 RW (IR)	0.22 µm	8.66 µinch	57 µm - 7300 µm	2.24 mils - 287.4 mils
IT 18-3000 (IR)	0.09 µm	3.54 µinch	18 µm - 3000 µm	0.71 mils - 118.1 mils
IT 150-15000	0.45 µm	17.72 µinch	150 µm - 15000 µm	5.91 mils - 590.6 mils
IT TW (IR)	0.01 µm	0.39 µinch	4 µm - 300 µm	0.16 mils - 11.81 mils
IT DW (IR)	0.06 µm	2.36 µinch	15 µm - 2000 µm	0.59 mils - 78.74 mils





SENSORS

AREA SENSORS – 3D WHITE LIGHT INTERFEROMETER

The 3D white light interferometers are available with 3 measurement ranges: 100 µm, 250 µm and 400 µm.

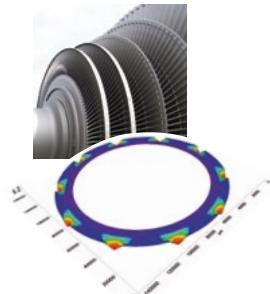
OBJECTIVE	Z-RESOLUTION	XY RESOLUTION	FIELD OF VIEW		WORKING DISTANCE	
2.5X	1 nm	0.039 µinch	9.24 µm	0.36 mils	7.12 mm x 5.34 mm	0.28 inch x 0.21 inch
5X	1 nm	0.039 µinch	4.62 µm	0.18 mils	3.56 mm x 2.67 mm	0.14 inch x 0.11 inch
10X	1 nm	0.039 µinch	2.31 µm	0.09 mils	1.78 mm x 1.34 mm	0.07 inch x 0.05 inch
20X	0.1 nm	0.0039 µinch	1.16 µm	0.05 mils	0.89 mm x 0.66 mm	0.04 inch x 0.03 inch
50X	0.1 nm	0.0039 µinch	0.61 µm	24.1 µinch	0.36 mm x 0.27 mm	14.1 mils x 10.6 mils
100X	0.1 nm	0.0039 µinch	0.23 µm	9.06 µinch	0.18 mm x 0.13 mm	7.09 mils x 5.27 mils
						2.0 mm
						0.08 inch

AREA SENSORS – 3D CONFOCAL MICROSCOPE

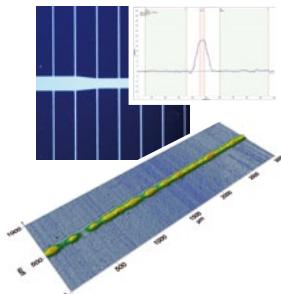
The 3D confocal microscope 400 µm uses a rotation Nipkow Disk and offers 400 µm range.

OBJECTIVE	Z-RESOLUTION	XY RESOLUTION	FIELD OF VIEW		WORKING DISTANCE	
20X	3 nm	0.12 µinch	1.16 µm	45.7 µinch	0.89 mm x 0.66 mm	0.04 inch x 0.03 inch
50X	2 nm	0.08 µinch	0.46 µm	18.1 µinch	0.36 mm x 0.27 mm	14.2 mils x 10.6 mils
100X	1 nm	0.039 µinch	0.23 µm	9.06 µinch	0.18 mm x 0.13 mm	7.09 mils x 5.12 mils

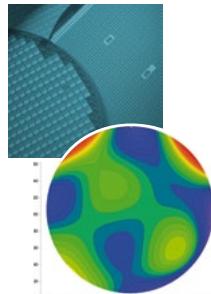
3D scan on a large gasket
Chromatic white light sensor
CHR-600



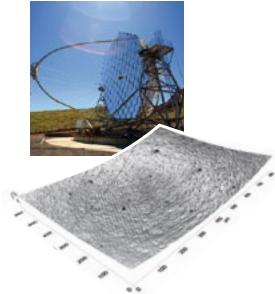
3D scan on a solar cell
Confocal laser sensor LT-9510



Wafer Thickness Map
Infrared interferometer IT-DW



Roughness of a mirror surface
3D white light interferometer



Surface of a gold coated via
3D confocal microscope

